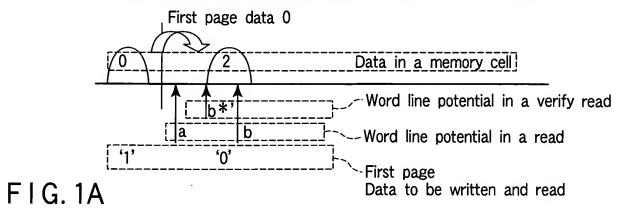
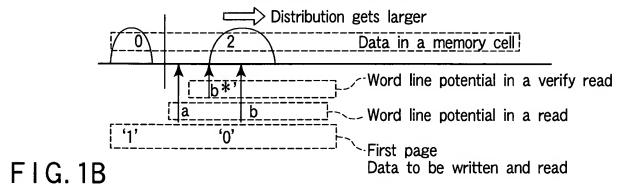
Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 1 of 42

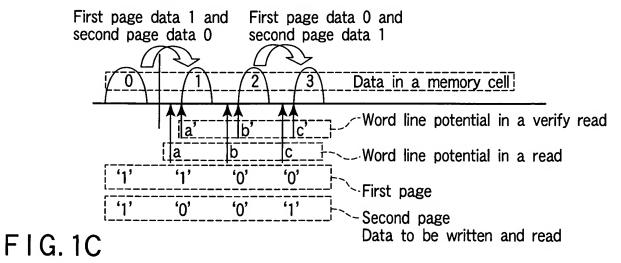
After writing the first page and before writing the second page



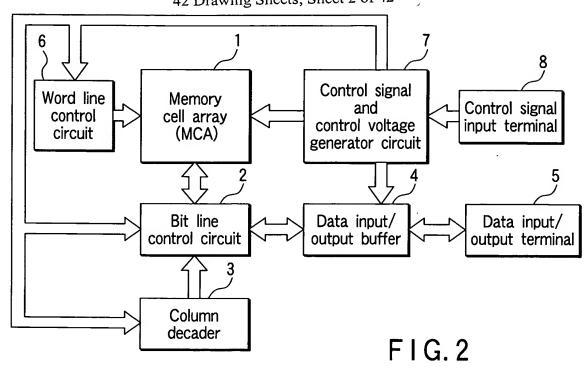
Before writing the second page and after writing the adjacent cells

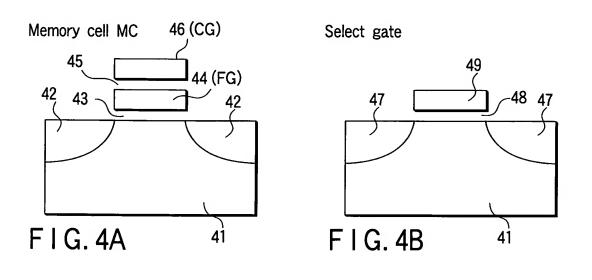


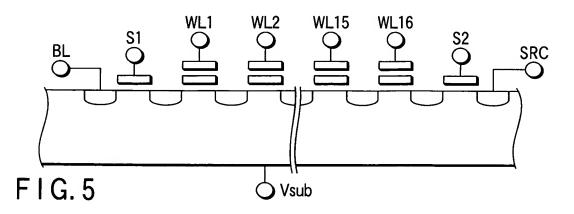
After writing the second page



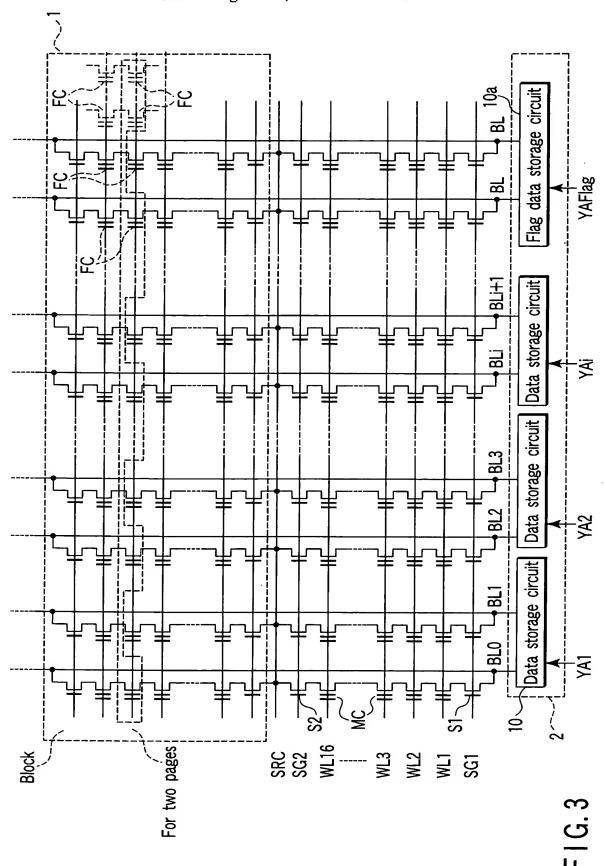
Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 2 of 42



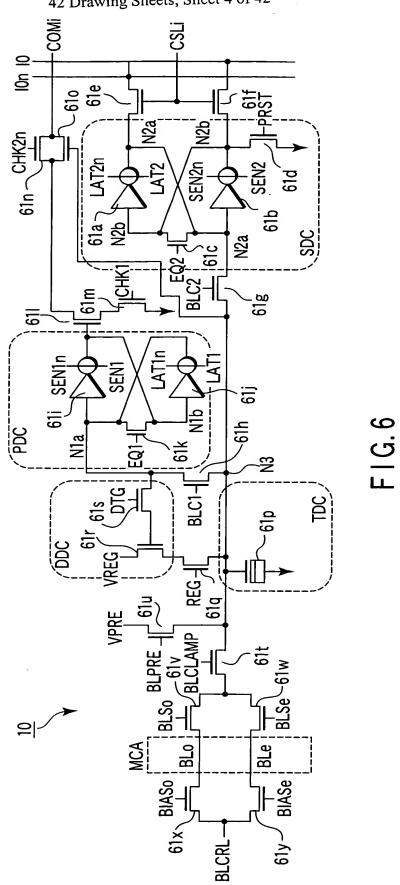




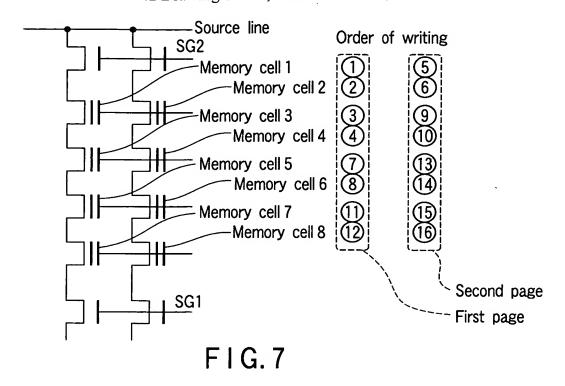
Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 3 of 42

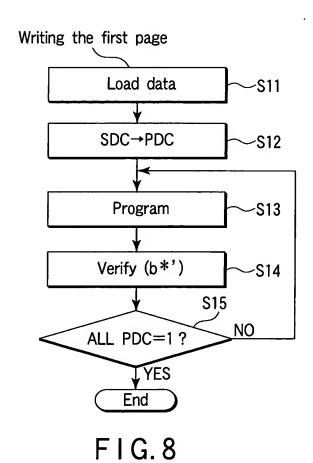


Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 4 of 42



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Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 6 of 42

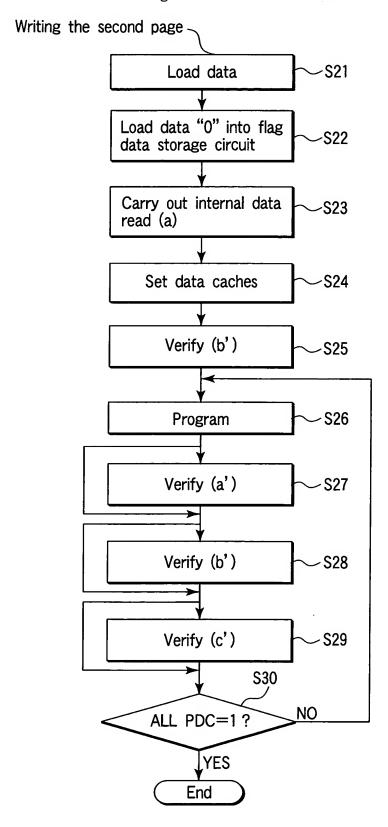


FIG. 9

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 7 of 42

After data load and internal read

SDC	Data in 0	- 1 1	nemory cell after writing  1 2 3  0 0 1	writing 3	Data to be written and read inputted from the outside world
PDC	0	0		-	Data read by internal read

After setting data caches

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 8 of 42

After internal data read into Copy data in TDC into SDC Copy data in PDC into TDC Copy data in PDC into DDC Copy data in TDC into PDC data in PDC into Data in memory cell after writing Copy data in SDC PDC VREG=L, REG=H VREG=L, REG=H TDC=H See Door က က PDC က ~ Data cache setting procedure က  $\sim$ SDC 

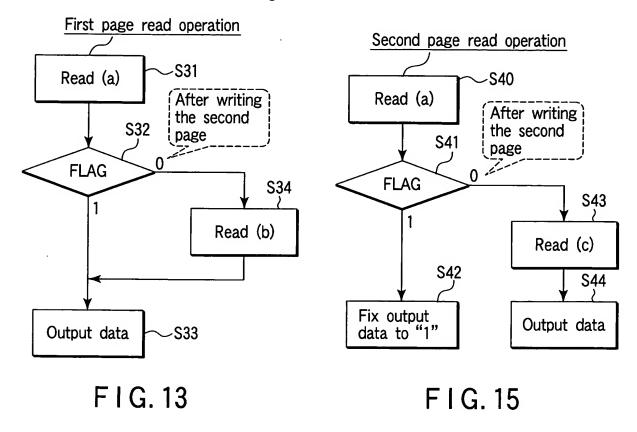
F1G 11

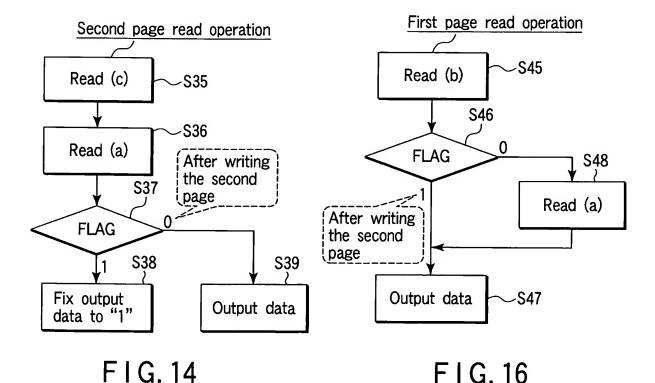
Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 9 of 42

$\overline{}$	_							
TDC=H	VREG=L, REG=H	Copy data in PDC into DDC	Copy data in TDC into PDC	TDC=L	VREG=H, REG=H	Copy data in PDC into DDC	Copy data in TDC into PDC	•
	0	0	0	0	0	0	0	
-	1	-	-	0	0	0	0	ပ္
1	1	1	-	0	0	0	0	TPC
	0)	0)	0	0			•	
0	0	0	0	0	0	0	0	
0	0	0	-	1	[-]	-	0	ည
0	0	0	1	-	1	1	0	PDC
-/	(I	1	0)	0	0)	0		
(1	1	(0	0	0	0	0	0	
0	0	0	0	0	0	1		DDC
0	0	0	0	0	0	1	-	10
	-		-		1	0)	0.	
0	0	0	0	0	0	0	0	
0	0	0	0	0	0	0	0	ဥ
-	-	-	_	-		-	-	SDC
_	-	-	-		-	-	-	

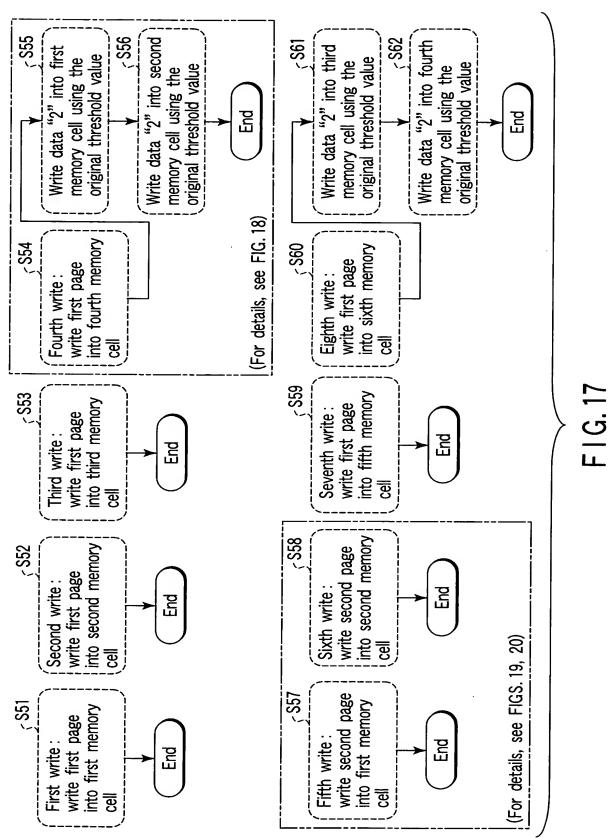
F1G. 12

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 10 of 42

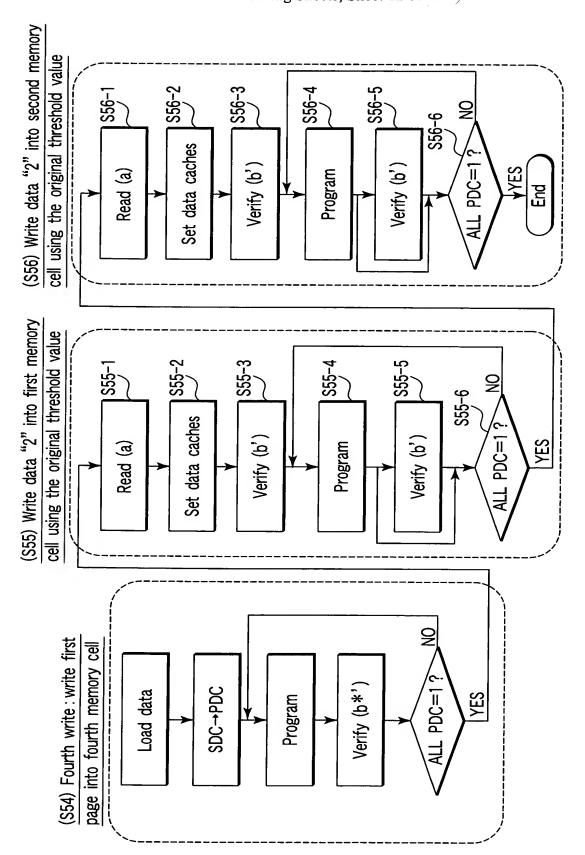




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F1G. 18

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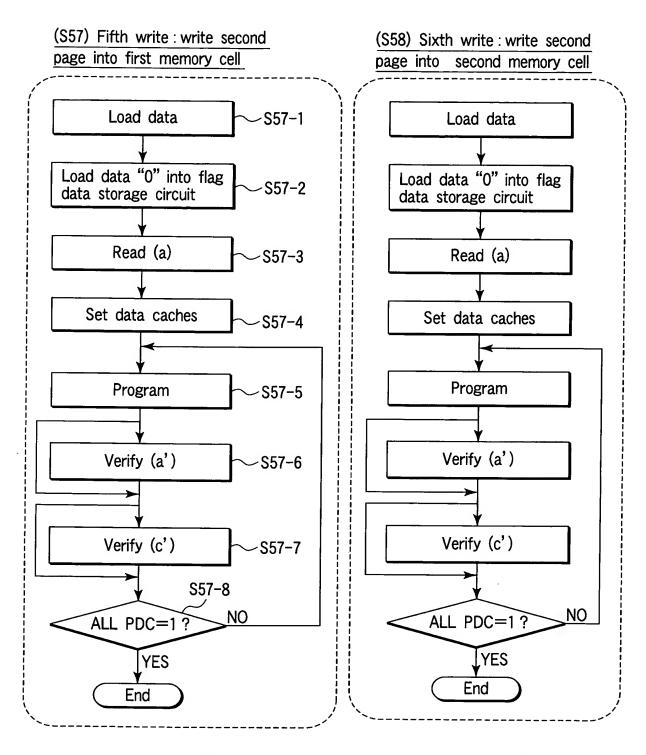


FIG. 19

FIG. 20

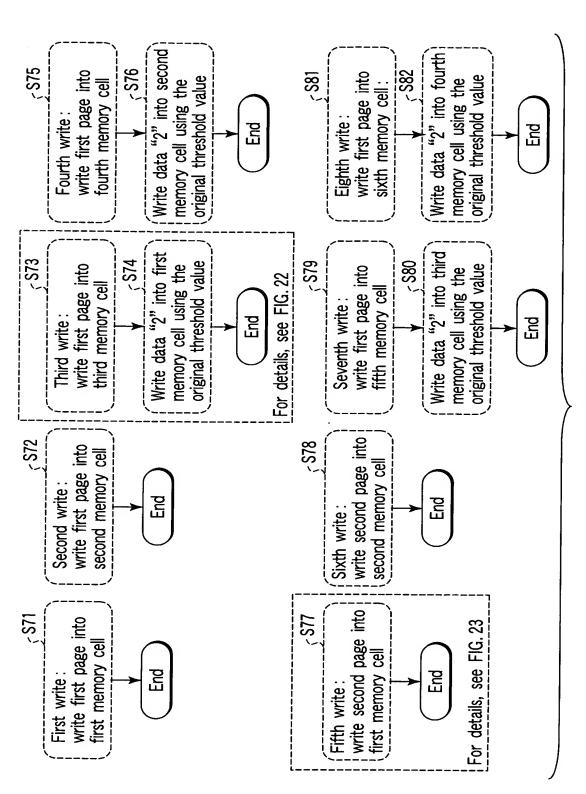


FIG. 21

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 15 of 42

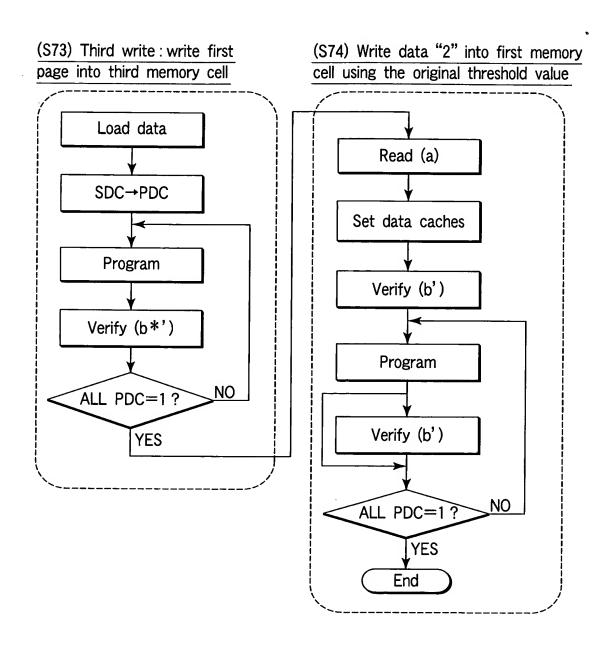
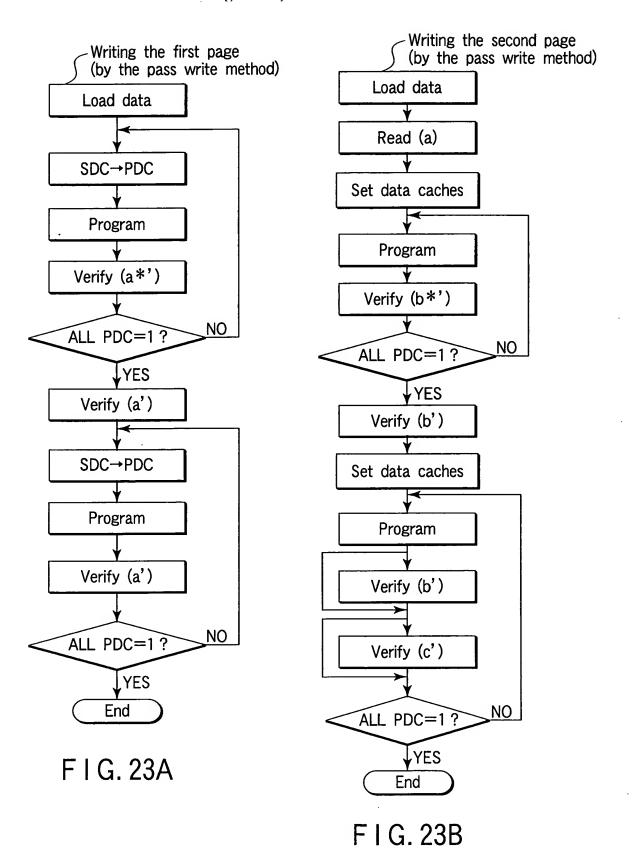


FIG. 22

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Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 17 of 42

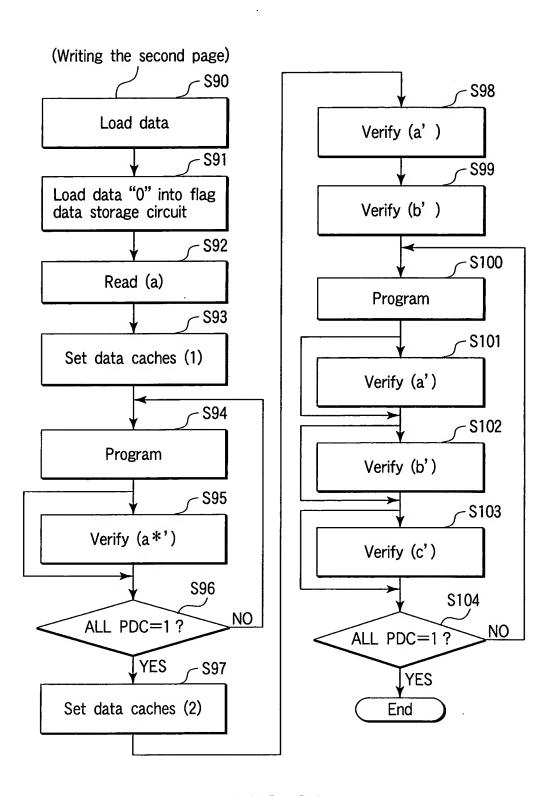


FIG. 24

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Data cache setting 1

חמום המחוף ארונון	م عدداا اق	_			
	Data in	in memory cell after writing	cell after	. writing	
	0	-	2	က	
SDC	-	0	0	-	
DDC	0	0	-	-	
PDC	-	0	-	_	1 : Write unselected 0 : Write

FIG. 25

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 19 of 42

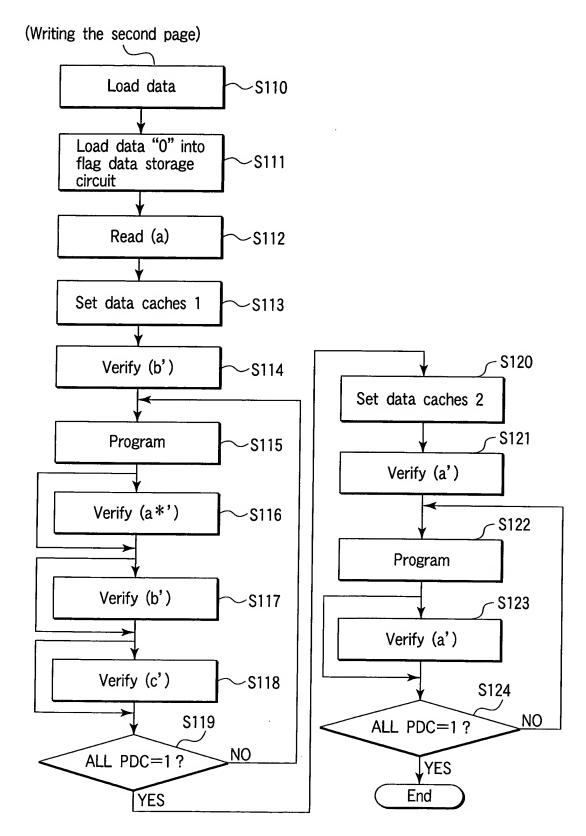


FIG. 26

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Used far charging in verifying memory cell data Used for charging in verifying memory cell data 1: Write unselected 0: Write Data in memory cell after writing 0 က 0 0 0 0 0 Data cache setting 1 0 0 0 200 SDC PDC

Data cache setting 2	Data in memory cell after writing	0 1 2 3	PDC 1 0 1:Write unselected 0:Write	ă	Data cache	Setting 2 Data ir	n memory 1	cell after	writing 3	1 : Write unselected 0 : Write
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FIG. 27B

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Noboru SHIBATA et al.
Semiconductor Memory Device...
EV 324 110 675 US
42 Drawing Sheets; Sheet 21 of 42

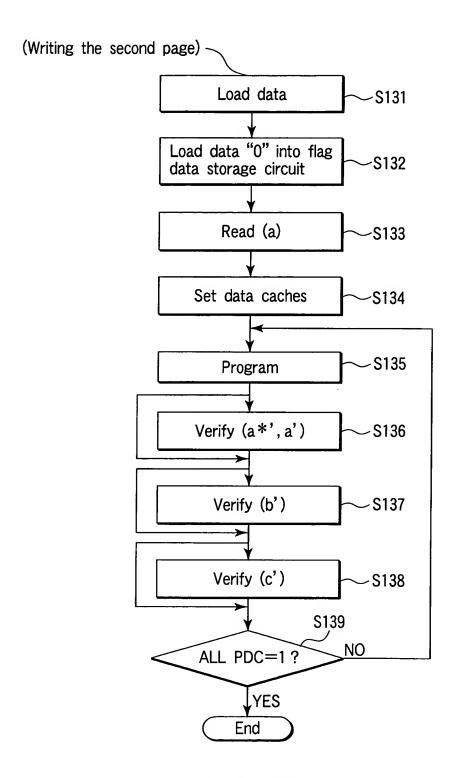


FIG. 28

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After data load and internal read

	Data in	memory	nemory cell after writing	writing	
	0	-	2	က	
SDC	-	0	0		Data to be written and read inputted from the outside world
PDC	0	0	ı	-	Data read by internal read

After data cache setting

	Data in	memory	memory cell after writing	r writing	
	0	-	2	က	
SDC	0	-	-	0	0 Used for charging in verifying memory cell data 2
DDC	-	0		-	Used for precharging bit line in programming and for charging in verifying memory cell data 1
PDC		1/0	0	0	0 1: Write unselected 0: Write

FIG. 29B

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	Precha	rge bit lin	Precharge bit line on the basis of the data in DDC	basis of the	ne data in	DDC
		Data	Data in memory cell after writing	cell after	writing	
		0	-	2	3	,
	Bit line	Λdd	F (Vss)	ρρΛ	Ndd	
L L	With Bl	LC1 = Vc	With BLC1 = Vclamp, connect PDC to bit line	ect PDC t	to bit line	
		Data i	Data in memory cell after writing	cell after	writing	
		0	-	2	8	
	Bit line	Ndd	0/Inter- mediate	0	0	
· L	During	program	recovery, t	ransfer da	ita in PDC	During program recovery, transfer data in PDC to DCC, invent data in DDC, and transfer the inverted data to PDC
		Data i	Data in memory cell after writing	cell after	writing	
		0	-	2	3	
0,	SDC	0	_	-	0	Used for charging in verifying memory cell data 2
	DDC	-	1/0	0	0	1 : Write unselected 0 : Write
	PDC	0	-	0	0	Used for precharging bit line in programming and for charging in verifying memory cell data 1
J						

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 24 of 42

Verify (a)
Charge bit line on the basis of data in PDC
Discharge bit line at a potential of WL = a\*
Invert data in PDC while discharging bit line

		Used for charging in verifying memory cell data 2	1 : Write unselected 0 : Write	Used far precharging bit line in programming and for charging in verifying memory cell data 1
writing	က	0	0	1
cell after	2	_	0	
in memory cell after writing	-	1	0/1	0
Data in	0	0	1	1
		SDC	DDC	PDC

Load the potential of bit line into TDC With VREG = H and REG = H, make TDC 1 when dynamic data is 1 Transfer data in PDC ta DDC and data in TDC to PDC

FIG. 31A

	Data in	memory	n memory cell after writing	writing	
	0	-	2	က	
SDC	0	1	-	0	Used far charging in verifying memory cell data 2
 DDC	_	0	0	_	User for precharging bit line in programming and for chagrining in verifying memory cell data 1
 PDC	-	0/1	1	1	1 : Write unselected 0 : Write

. I.G. 31B

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With WL = a', discharge bit line With VREG = H and REG = H, set 1 in TDC when dynamic data is 1 Transfer data in PDC to DDC Transfer data in TDC to PDC

		Used for charging in verifying memory cell data 2	1 : Write unselected 0 : Write	Used for precharging bit line in programming and for charging verifying memory cell data 1
. writing	က	0	0	-
cell after	2	_	0	_
in memory cell after writing		_	0/1	0
Data in	0	0		-
		SDC	DDC	PDC

Transfer data in DDC to PDC Then, transfer data in PDC to DDC

F1G. 32A

		Used for charging in verifying memory cell data 2	Used for precharging bit line in programming and for charging in verifying memory cell data 1	1 : Write unselected 0 : Write
/riting	က	0	L V.	0
Data in memory cell after writing	2	-	-	0
y cell				
n memor	-	-	0	0/1
Data in	0	0	-	1
		SDC	DDC	PDC

FIG. 32B

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With memory cell data 1, all of the writing with verify (a\*) is completed (the writing with verify (a') might nat be completed)

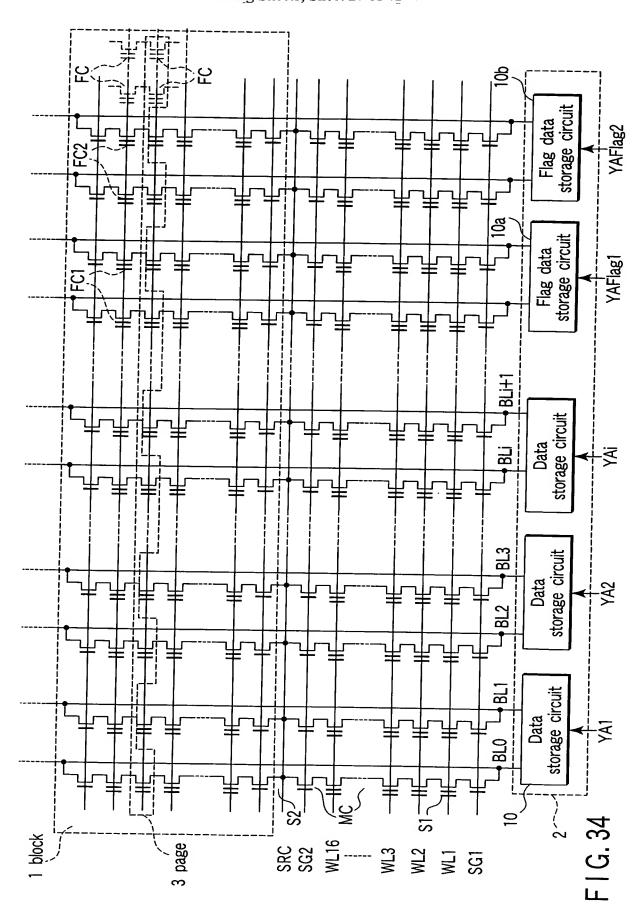
	Data in m		emory cell after writing	writing	
	0	_	2	က	
SDC	0	1	-	0	Used far charging in verifying memory cell data 2
DDC	<del></del>	0	1	l	Used for precharging bit line in programming and for charging in verifying memory cell data 1
PDC	-	<b>,_</b> _	0	0	1 : Write unselected 0 : Write

With memory cell data 1, all of the writing with verify (a') is completed (the writing with verify (a') might not be completed)

	Data in men	memory	nory cell after writing	· writing	
	0	_	2	ന	
SDC	0	-	-	0	Used for charging in verifying memory cell data 2
DDC	-		_	_	Used for precharging bit line in programming and for charging in verifying memory cell data 1
PDC	-		0	0	1 : Write unselected 0 : Write

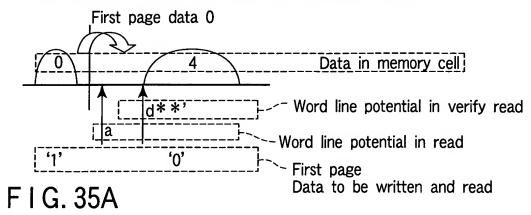
I G. 33B

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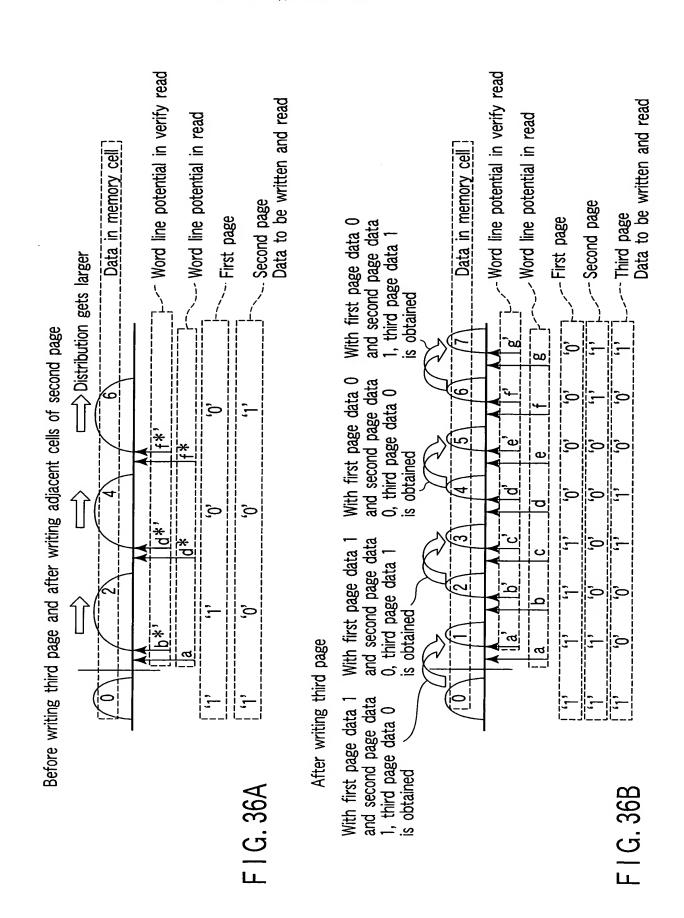
(After writing first page and before writing second page)



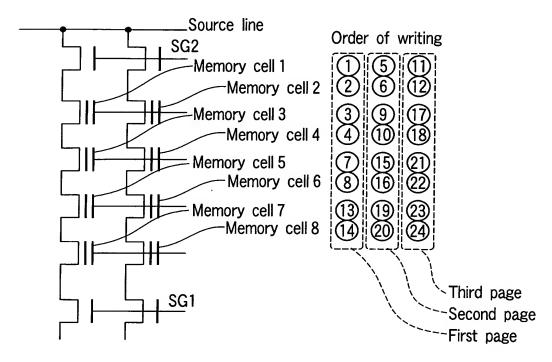
After writing first page, before writing second page, and after writing adjacent cells of first page Distribution gets larger Data in memory cell; Word line potential in verify read Word line potential in read '0' First page Data to be written and read F I G. 35B After writing second page, before writing third page, and after writing adjacent cells of second page With first page data 1, With first page data 0, second page data 0 is second page data 1 is obtained obtained 6 Data in memory cell; Word line potential in verify read Word line potential **'**0' **'**0' in read First page **'0' '0'** Second page Data to be FIG. 35C

written and read

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F I G. 37A

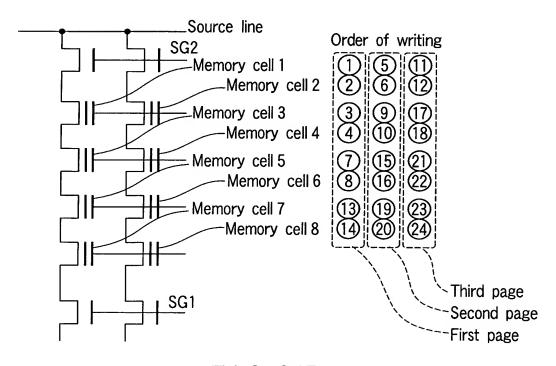
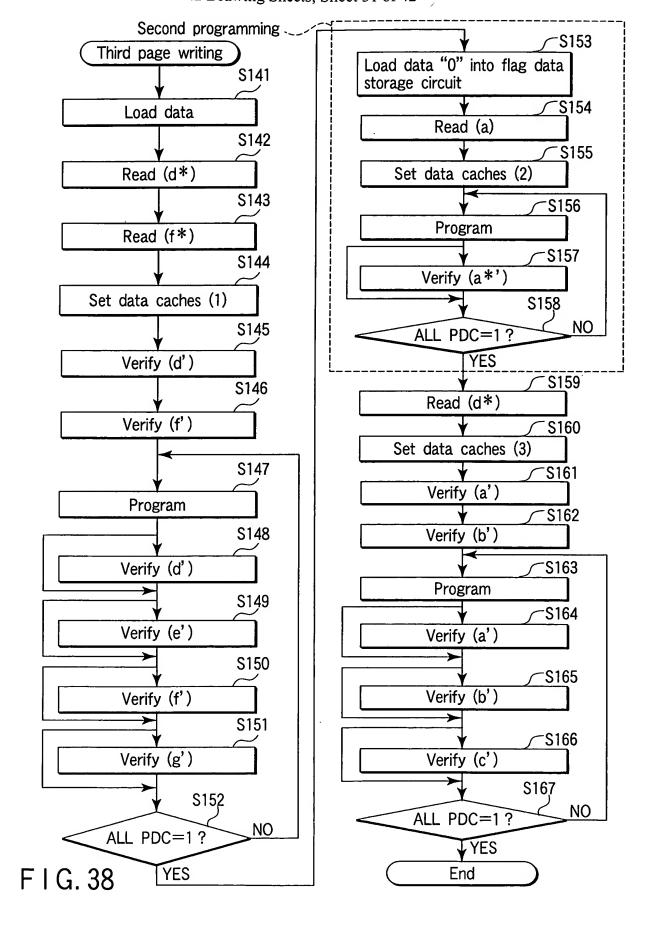


FIG. 37B

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After third page data load internal read 1

		Data in		mory	cells	memory cell after writing	writin	<b>₽</b> 0	
	0	1	2	3	4	3 4 5 6	9	7	
SDC	1	0	0	-	-	0	0	-	1 0 0 1 Data to be written and read inputted from the outside world
DDC	0	0	0	0	0	0 0 0 1	-	-	1 Data to be read by internal read
PDC	0	0	0	0	-	-	-	-	Data to be read by internal read

After third page data cache setting 1

	ם	Data in		mory	s lleo	memory cell after writing	writin	<b>₽</b> 0	
	0	-	2	3	4	3 4 5 6 7	ပ	2	
SDC	-	-	-	-	-	-	0	0	1 1 1 0 0 Used far charging in verifying memory cell data items 5, 4
DDC	0	-	-	0	0	-	_	0	0 0 1 1 0 Used for charging in verifying memory cell data 6 Forced to be at VSS in verifying memory cell data 4
PDC	•	-	,	-	0	0	0	0	1 0 0 0 1: Write unselected 0: Write

. I G. 39B

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After third page data cache setting 2

	٥	Data in		mory	s lles	memory cell after writing	writin	ρ.0	
	0	1	2	3	4	5	9	7	
SDC	-	1	0	0	0	0 0	0	0	
DDC	0	1	1	0	0	-	-	0	
PDC	_	0	-	-		-	-	-	1 : Write unselected 0 : Write

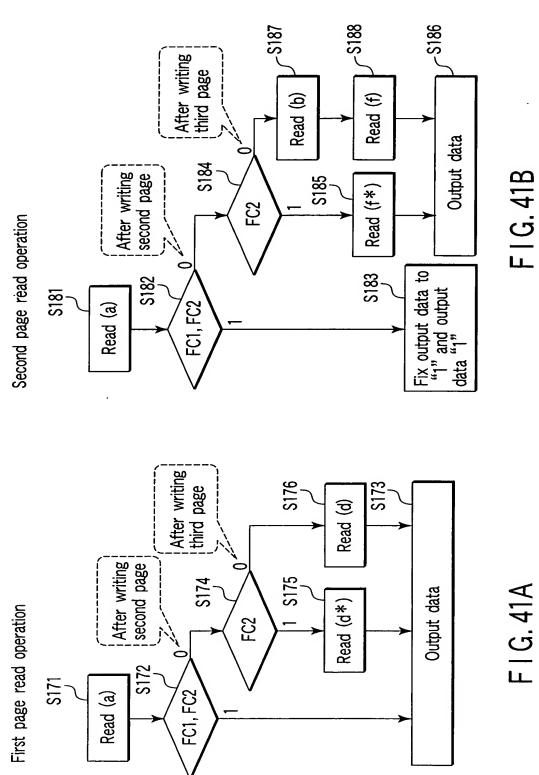
After third page data cache setting 3

FIG. 40A

	L-J	Data i	in mer	mory	s lleo	memory cell after writing	writin	ρø	
	0	-	2	က	4	2 3 4 5 6 7	9	7	
SDC	-	1	0	0	0	0	0	0	0 0 0 0 Used for charging in verifying memory cell data 1
DDC	0	-	-	0	0	1	-	0	1 0 0 1 1 0 Used for charging in verifying memory cell data 2
PDC	-	0	0	0	1	-	-	-	0 0 1 1 1 Write unselected 0:Write

I G. 40B

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## Third page read operation

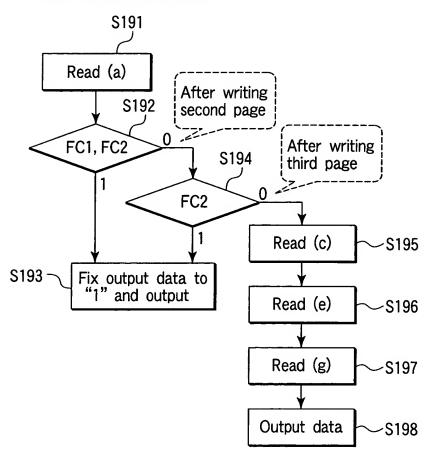


FIG. 42

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After data load and internal read

	Data in	_	nemory cell after writing	writing	
	0	1	. 2	3	
SDC	1	0	0	-	Data to be written and read inputted from the outside world
PDC	0	0	1	-	Data read by internal read

F I G 43A

After setting data caches

	Data in m	memory	nemory cell after writing	writing	
	0	-	2	3	
SDC	-	-	0	0	Used for charging in verifying memory cell data 1
DDC	0	0	-	0	Used for charging in verifying memory cell data 2
PDC	1	0	0	0	1 : Write unselected, 0 : Write

F I G. 43B

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Verify (a\*') Charge bit line on the basis of data in SDC Discharge bit line at a potential of WL=a\*'

	Data in	Data in memory cell after writing	cell after	writing	
	0		2	က	
SDC	1	1	0	0	Used for charging in verifying memory cell data 1
DDC	0	0	1	0	Used for charging in verifying memory cell data 2
PDC	1	0	0	0	1 : Write unselected, 0 : Write

F1G. 44A

Set Vdd in TDC and transfer the potential of bit line to TDC when BLCLAMP is H With VREG=H, REG=H, make TDC 1 when dynamic data is 1 Transfer data in PDC to DDC and data in TDC to DDC

	Data ir	n memory	Data in memory cell after writing	writing	
	0	-	2	က	
SDC	1	-	0	0	Used for charging in verifying memory cell data 1
DDC	1	0	0	0	0 1 : Write unselected, 0 : Write
PDC	0	0/1	-	0	Used for charging in verifying memory cell data 2 When threshold voltage in memory cell into which data 1 is written exceeds a*'→1

F I G. 44B

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Discharge bit line at a potential of WL=a' Set Vdd in TDC and transfer the potential of bit line to TDC when BLCLAMP is H With VREG=H, REG=H, make TDC 1 when dynamic data is 1 Transfer data in PDC to DDC and data in TDC to DDC

	Dz	ita in mer	Data in memory cell after writing	after writi	ing	
	0	1pass	1 pass 1 fail 2	2	က	
SDC	-	-	-	0	0	Used for charging in verifying memory cell data 1
DDC	0	_	0/1	•	0	Used for charging in verifying memory cell data 2 When threshold voltage in memory cell into which data 1 is written exceeds a*'→1
PDC	1	-	0	0	0	0 1:Write unselected, 0:Write

F1G. 45A

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 39 of 42

Used for charging in verifying memory cell data 2 When threshold voltage in memory cell into which

0

7

0

200

0

0

0

SDC

data 1 is written exceeds  $a^*$   $\rightarrow$  1

1: Write unselected, 0: Write

0

0

0

PDC

Used for charging in verifying memory cell data

Transfer data in DDC to TDC, PDC to DDC and TDC to PDC during the discharge Set Vdd in TDC and transfer the potential of bit line to TDC when BLCLAMP is H With VREG=H, REG=H, make TDC 1 when dynamic data is 1 Transfer data in PDC to DDC and data in TDC to DDC Charge bit line on the basis of data in DDC Discharge bit line at a potential of WL=b'

3	3
after writi	2pass
nory cell after	2fail
Data in mer	-
Da	0

F1G 45B

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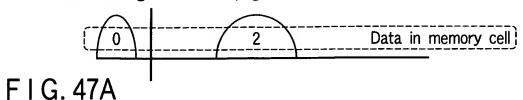
Transfer data in DDC to TDC, PDC to DDC and TDC to PDC during the discharge Set Vdd in TDC and transfer the potential of bit line to TDC when BLCLAMP is H With VREG=H, REG=H, make TDC 1 when dynamic data is 1 Charge bit line Discharge bit line at a potential of WL=c'

	Da	Data in memory cell after writing	nory cell a	after writi	Bu	
	0		1 2 3fail 3pass	3fail	3pass	
SDC	1	-	0	0	0	0 Used for charging in verifying memory cell data 1
DDC	0	0/1	-	0	0	Used for charging in verifying memory cell data 2 When threshold voltage in memory cell into which data 1 is written exceeds $a^* \rightarrow 1$
PDC	-	0	0	0	-	1 : Write unselected, 0 : Write

F1G 46

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Before writing the second page



After writing the second page

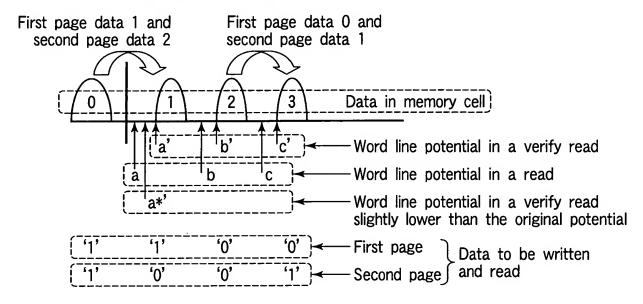
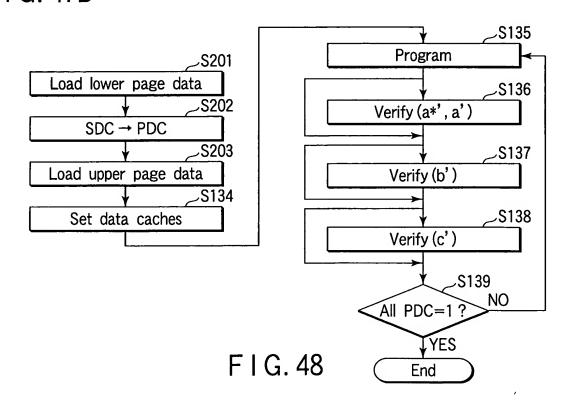


FIG. 47B



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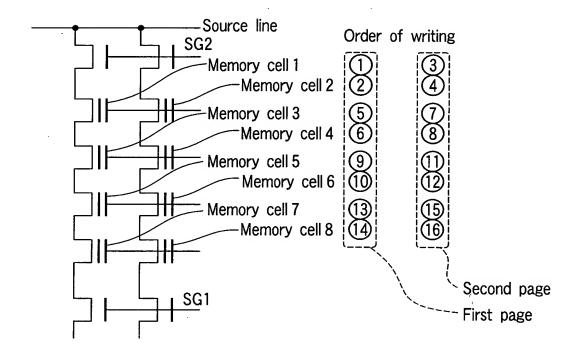


FIG. 49